EAST Search History

Ref #	Hits	Search Query	DBs	Default Operato r	Plural s	Time Stamp
L1	438	257/363.ccls.	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:18
L2	1909	257/355.ccls.	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON-	2007/04/02 09:18
L3	265	257/275.ccls.	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:18
L4	31872	Asano.in.	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:18
L5	20	4 and operating adj region and electrode and pad	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:26
L6	0	("6946891").URPN.	USPAT	OR	OFF	2007/04/02 09:21

EAST Search History

L7	1	4 and (operating adj region same electrode adj pad same wirings)	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:27
L8	0	1 and (operating adj region same electrode adj pad same wirings)	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:27
L9	1	2 and (operating adj region same electrode adj pad same wirings)	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:27
L10	0	3 and (operating adj region same electrode adj pad same wirings)	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:27
L11	23	2 and (source with electrode and gate with electrode and drain with electrode and wiring with electrode and protect\$4 with (impurity))	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:29

EAST Search History

L12	13	1 and (source with electrode and gate with electrode and drain with electrode and wiring with electrode and protect\$4 with (impurity))	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:32
L13	3	3 and (source with electrode and gate with electrode and drain with electrode and wiring with electrode and protect\$4 with (impurity))	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:29
L14	1	1 and (source with electrode and gate with electrode and drain with electrode and wiring with electrode and (protect\$4 with (impurity) with high adj concentration))	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:33
L15	3	2 and (source with electrode and gate with electrode and drain with electrode and wiring with electrode and (protect\$4 with (impurity) with high adj concentration))	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:33
L16	2	3 and (source with electrode and gate with electrode and drain with electrode and wiring with electrode and (protect\$4 with (impurity) with high adj concentration))	US-PGPU B; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/04/02 09:33

4/2/07 9:40:36 AM